## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10707960	CHIBA ET AL.	
Examiner Rajan, Kaj	Art Unit	
Rajan, Kai <del>Kowalewski, Filip A</del>	3736	

SEARCHED					
Class	Subclass	Date	Examiner		
600	300-301	3/2007	KR		
607	3, 60	3/2007	KR		
128	903-905; 920	3/2007	KR		

SEARCH NOTES				
Search Notes	Date	Examiner		
Search Updated	3/2007	KR		

	INTERFERENCE SEARCH			
Class	Subclass	Date	Examine	